

Test Probe INGUN E-Type

E-075 270 026 E 2000

Item E-075-0084



GO TO PRODUCT

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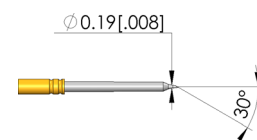
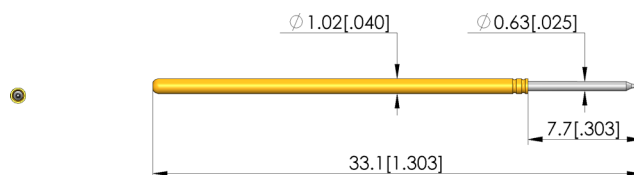
- Highest contact reliability under challenging test conditions without additional stress on the DUT: up to 25% larger contact surface between test probe and DUT
- When hitting the test surface a spring force up to 100% higher than a standard GKS is available, but the same spring force as a standard GKS is achieved at the working stroke.



INGUN SELECTION



1:1



General data

Product group:	ICT / FCT (in-circuit test and function test)
Sub-product group:	INGUN E-TYPE®
Series:	E-075
Grid:	1.91 mm [75.1 mil]
Contacting from:	Pad
Magnetic:	Yes
Installation type:	Plug-in
Quick-exchange system:	Yes
Adjustable installation height:	No
Non-rotating:	No
Compatible receptacle(s):	KS-075
Min. temperature:	-40 °C [-40 °F]
Max. temperature:	80 °C [176 °F]
RoHS-compliant:	Yes

Tip style data

Tip style:	70 asymmetric slanted needle tip
Tip diameter:	0.2 mm [.007 in]
Tip style surface:	E palladium / nickel
Tip style material:	2 steel

Electrical data

Current load capacity / rated current:	3 A
Typical resistance (Ri):	20 mOhm

Mechanical data

Total length:	33.1 mm [1.3 in]
Barrel diameter:	1.02 mm [.04 in]
Maximum stroke:	6.35 mm [.25 in]
Spring pre-load:	1.11 N [3.99 ozf]
Collar height:	00
Spring force at working stroke:	2 N [7.19 ozf]
Recommended working stroke:	4.3 mm [.169 in]

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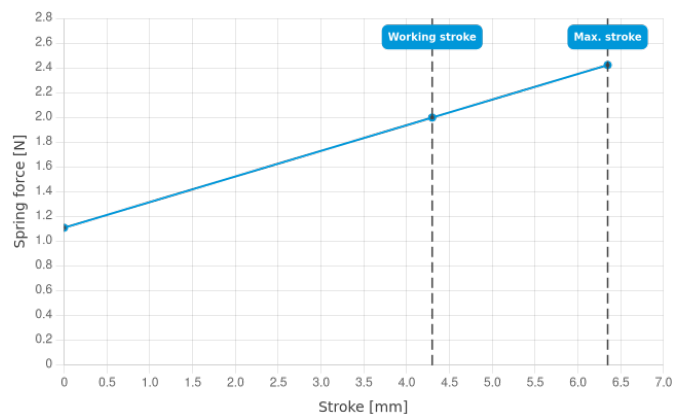
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Prices and delivery times on request.
Technical changes reserved. 11/25_GB

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